

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)	Application	OFGS File No. <b>P/4303-32</b>
	Applicant <b>Simon FRANK et al.</b>	
	Filing Date <b>Herewith</b>	Group Art Unit <b>3612</b>

### U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
<b>KBL</b>	US-6,174,009 B1	1/2001	McKEON			
	US-5,876,077	3/1999	MISKECH et al.			
	US-3,842,222	10/1974	HOGLAND			
	US-3,897,095	7/1975	GLANCE et al.			
	US-3,912,295	10/1975	EGGERT, Jr.			
	US-3,998,485	12/1976	PUTTER et al.			
	US-4,023,652	5/1977	TORKE			
	US-4,272,114	6/1981	HIRANO et al.			
	US-4,413,856	11/1983	McMAHAN et al.			
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	US-5,314,229	5/1994	MATUZAWA et al.			
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	US-5,732,801	3/1998	GERTZ			
	US-5,772,267	6/1998	HEIM et al.			

### FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
<b>KBL</b>	546 352	6/1993	Europe				
	11-208393	8/1999	Japan				
	55-136660	10/1980	Japan				
	WO 98/39197	9/1998	PCT				

Examiner

**KBL**

Date Considered

**5-20-04**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
KBC	US-5,853,195	12/1998	LE et al.	[Handwritten mark]	[Handwritten mark]	
	US-5,876,078	3/1999	MISKECH et al.			
	US-6,106,039	8/2000	MAKI			
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	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
KBC	2-175452	7/1990	Japan	[Handwritten mark]	[Handwritten mark]		
	19517921	11/1996	Germany				
	0854066	12/1997	Europe				
	19700022	7/1998	Germany				
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	19913078	9/2000	Germany				
	2002-104107	4/2002	Japan				

  

Examiner <b>KBC</b>	Date Considered <b>5-26-04</b>
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U. S. DEPARTMENT OF COMMERCE  
Sheet 1 of 1

PATENT AND TRADEMARK OFFICE

**LIST OF REFERENCES CITED BY APPLICANT**

Atty Docket No.: 4780-23  
Serial No.: n/a  
Applicant: Simon FRANK

Filing Date: concurrently

Group Art:

**U.S. PATENT DOCUMENTS**

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
KBO	AA	6,174,009 B1	01/16/2001	McKeon			
1	AB	5,876,077	03/02/1999	Miskech, et al.			
	AC						
	AD						
	AE						

**FOREIGN PATENT DOCUMENTS**

*Ex. Intls.		Document No.	Date	Country	Name	Class	Subclass	Translation Yes/No
KBO	AF	546 352	06/16/1993	Europe				
	AG	11-208393	08/03/1999	Japan				
	AH	55-136660	10/24/1980	Japan				
	AI	WO 98/39197	09/11/1998	PCT				

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AJ		
	AK		
	AL		

EXAMINER: KBODATE CONSIDERED: 5.26.04

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